

Near Field Scanning Optical Microscopy (NSOM) system

Description:

The MultiView 2000™ series is a premium ultra-sensitive scanned probe microscope with a variety of modes of AFM/SPM/NSOM imaging. The MultiView 2000™ can achieve integration with AFM/SPM, without compromising optical performance. Nanonics has designed The MultiView 2000™ for excellence in scanned probe microscopy while allowing for near-field and far-field optical NSOM/Raman imaging without perturbation.

Specialized Scanning:

- Two award-winning Nanonics' FlatScan™ stages for Tip and Sample Scanning.
- Up to 100 microns in X,Y & Z axis per scanner.
- Up to 200 microns in X,Y & Z axis in combined scanners.
- High step resolution and high resonance frequency.
- Unique Large Z range of 100 μm .

Feedback:

- The accepted ultimate in feedback of tuning forks without any optical interference.
- Optical & other Online

Integrations:

- Free optical axis for transparent integration with true confocal optical microscopes of upright, inverted and dual configurations.
 - Powerful objectives of high magnification (100x) and Large NA (0.75) including water immersion objectives from top.
 - Raman microscopes, electron and ion optical microscopes, environmental glove box and high vacuum chambers.
- Samples:
- Odd size and large samples including hanging geometries.

Probes:

All forms of cantilevered glass probes from Nanonics' exclusive NanoToolKit™; Nanosensors including Akiyama tuning forks probes and Si probes.

